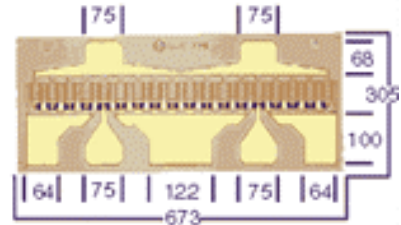


Features:

- +30.0 dBm typical Output Power at 12 GHz
- 10.0 dB typical Small Signal Gain at 12 GHz
- 55% typical PAE at 12 GHz
- 0.3 x 1200 Micron Refractory Metal/Gold Gate
- Sorted into 20 mA Idss Bin Ranges
- Excellent for High Power, Gain, and High Power Added Efficiency
- Ideal for Commercial, Military, Hi-Rel Space Applications



Chip Dimensions: 673 x 305 microns
Chip Thickness: 100 microns

Description:

The MwT-PH8 is a AlGaAs/InGaAs PHEMT (Pseudomorphic-High-Electron-Mobility-Transistor) device whose nominal 0.3 micron gate length and 1200 micron gate width make it ideally suited for applications requiring high-gain and power up to 20 GHz frequency range with power outputs ranging from 800 to 1000 milli-watts. The device is equally effective for either wideband (e.g. 6 to 18 GHz) or narrow-band applications. The chip is produced using MwT's reliable metal systems and all devices from each wafer are screened to insure reliability. All chips are passivated using MwT's patented "Diamond-Like Carbon" process for increased durability.

Electrical Specifications:

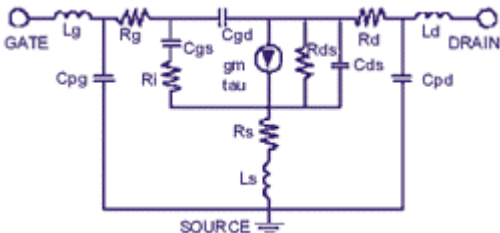
- *at Ta= 25 °C*

SYMBOL	PARAMETERS & CONDITIONS	FREQ	UNITS	MIN	TYP
P1dB	Output Power at 1dB Compression Vds=7.0 V Ids=0.6xIDSS=240 mA	12 GHz	dBm	29.0	30.0
SSG	Small Signal Gain VDS=7.0 V Ids=0.6xIDSS=240 mA	12 GHz	dB	9.0	10.0
PAE	Power Added Efficiency at P1dB VDS=7.0 V Ids=0.6xIDSS=240 mA	12 GHz	%		55
IDSS	Recommended IDSS Range for Optimum P1dB		mA		280-460

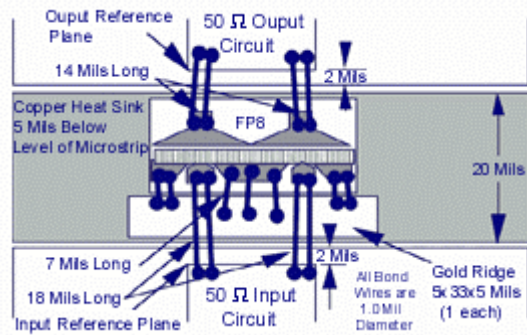
DC Specifications: • at $T_a = 25\text{ }^\circ\text{C}$

SYMBOL	PARAMETERS & CONDITIONS	UNITS	MIN	TYP	MAX
IDSS	Saturated Drain Current $V_{ds}=4.0\text{ V}$ $V_{gs}=0.0\text{ V}$	mA	240		600
Gm	Transconductance $V_{ds}=2.5\text{ V}$ $V_{gs}=0.0\text{ V}$	mS	240	320	
Vp	Pinch-off Voltage $V_{ds}=3.0\text{ V}$ $I_{ds}=8.0\text{ mA}$	V		-1.2	-2.5
BVGSO	Gate-to-Source Breakdown Voltage $I_{gs} = -1.4\text{ mA}$	V	-6.0	-12.0	
BVGDO	Gate-to-Drain Breakdown Voltage $I_{gd} = -1.4\text{ mA}$	V	-10.0	-13.0	
Rth	Chip Thermal Resistance	C/W		40*	

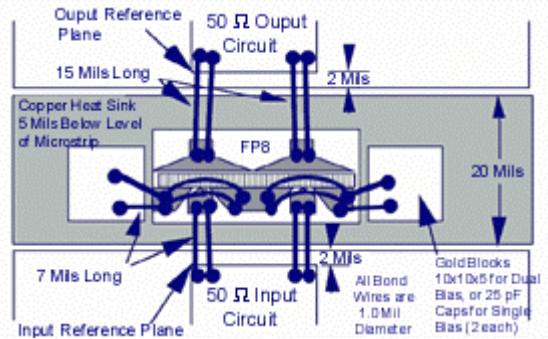
* Overall Rth depends on case mounting

DEVICE EQUIVALENT CIRCUIT	PARAMETER	VALUE	
	Source Resistance	R_s	0.30 ohm
	Source Inductance	L_s	0.055 nH
	Drain-Source Resistance	R_{ds}	200 ohm
	Drain-Source Capacitance	C_{ds}	0.15 pF
	Drain Resistance	R_d	0.3 ohm
	Drain Pad Capacitance	C_{pd}	0.20 pF
	Drain Inductance	L_d	0.1 nH
	Gate Bond Wire Inductance	L_g	0.12 nH
	Gate Pad Capacitance	C_{pg}	0.25 pF
	Gate Resistance	R_g	0.20 ohm
	Gate-Source Capacitance	C_{gs}	2.50 pF
	Channel Resistance	R_i	4.00 ohm
	Gate-Drain Capacitance	C_{gd}	0.13 pF
	Transconductance	g_m	280 mS
	Transit Time	τ	1.0 psec

MwT-PH8 DUAL BIAS



MwT-PH8 SELF BIAS



MAXIMUM RATINGS AT Ta = 25 °C

Symbol	Parameter	Units	Cont Max1	Absolute Max2
VDS	Drain to Source Volt.	V	7.5	8.0
Tch	Channel Temperature	°C	+150	+175
Tst	Storage Temperature	°C	-65 to +150	+175
Pin	RF Input Power	mW	240	360
Pt	Total Power Dissipation	mW	2700	3300

Notes:

1. Exceeding any one of these limits in continuous operation may reduce the mean-time-to-failure below the design goal.
2. Exceeding any one of these limits may cause permanent damage.

BIN SELECTION

MwT-PH8	Old Bin	3	4	5	6	7	8	9	10	11
	New Bin	A	A	A	B	B	B	B	C	C
Idss	280-	300-	320-	340-	360-	380-	400-	420-	440-	
Range	300	320	340	360	380	400	420	440	460	

BIN ACCURACY STATEMENT: Due to the effects of temperature, dc loading and probe tip varnishing, the IDSS from the "on wafer" probing of any MwT device may differ. After it has been attached to a proper heat sink and tested in an RF or DC circuit. Because of the aforementioned effects, the IDSS distribution may deviate as much as +/- 1 bin within the range identified on the label of Each die shipping container, and +/- 2 bins within the selected range.

ORDERING INFORMATION:

When placing order or inquiring, please specify BIN range, wafer number, if known, and visual screening level required. For details of BIN Selection and Safe Handling Procedure please see supplementary information in available PDF on our website www.mwtinc.com